





Visualizing Electrical Breakdown and ON/OFF States in Electrically Switchable Suspended Graphene Break Junctions

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Supporting Information

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Sample

Si/SiO₂ (300 nm) substrate

1-5 layer graphene (mechanical exfoliation) 2 methods:

- EBL and 120 nm oxide etching
- Exfoliaton on prepatterned substrate (250 nm deep)
 - 10/70 nm Ti/Au with shadow mask
- $G_{_{2p}} \sim 0.5 \text{ mS}$

Electromigration (in situ SEM vid): High vacuum: 10⁻⁶ Torr ~ 4 V pulse \rightarrow ~2mA/µm ~ 2 V test voltage Start: center/edge (depend on T, defects etc.)







Switch

- UHV needed (clean sample)
 - Atomic motion
 - Chemical rearrangement Both
- Open @±4V ('ON') 25-40µS Close (8V pulse) ('OFF') ~1µS
- Hunderds of cycles
 - Less cycle before failure than @ nonsuspended samples
- Control device: w/o graphene Almost zero current @10V Breakdown @210 V





Temperature dependence



No switching @4.5K Very rare under 280 K Estimated max freq: ~ 1 MHz (graphene cantilever) Another time scale ~ 1 ms Measured timescale: ~100ms – 1s >> 1 ms Elastic properties: weak T dependence Switching not limited by nanomechanical motion, but atomic motion/ chemical rearrangements (~eV energy scale)

